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(54) **Title:** ENHANCED CHIP SELECT SIGNAL TRAINING

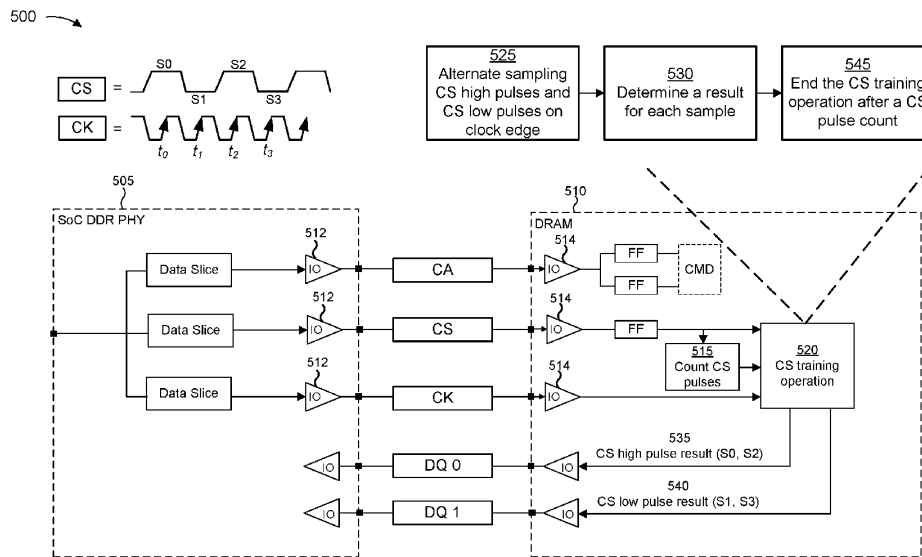


FIG. 5

(57) **Abstract:** In some aspects, an electronic device may receive a clock signal having a first frequency. The electronic device may receive, for a chip select training operation, a chip select signal having a pattern including high pulses and low pulses. The electronic device may perform, for a sampling window, the chip select training operation using the clock signal and the chip select signal, wherein the sampling window includes a quantity of pulses of the chip select signal. The electronic device may provide, via a first data in or out (DQ) pin, an indication of a first result of the chip select training operation for the high pulses of the chip select signal. The electronic device may provide, via a second DQ pin, an indication of a second result of the chip select training operation for the low pulses of the chip select signal. Numerous other aspects are described.

[Continued on next page]

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